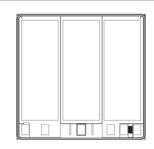
## 650 V, 300 A Field Stop Trench IGBT with Solderable Top Metal



## **ON Semiconductor®**

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# G TS<sub>A</sub> CS<sub>E</sub>



#### Features

- AEC–Q101 Qualified
- Maximum Junction Temperature 175°C
- Positive Temperature Coefficient
- Easy Paralleling
- Short Circuit Rated
- Very Low Saturation Voltage: VCE(SAT) = 1.5 V (Typ.) @ IC = 300 A
- Optimized For Motor Control Applications
- Integrated Temp Sensor And Current Sensor
- Emitter Pad Covered With Solderable Metal Layer

#### Applications

- Automotive Traction modules
- General Power Modules

#### **ORDERING INFORMATION**

Part Number	PCGA300T65DF8M1					
Packing	Water (sawn on foil)					
	mils	μm				
Die Size	472×472	12,000 × 12,000				
Emitter Attach Area	3 × (141 × 383)	3 × (3,580 × 9,720)				
Gate / Sensor Pad Attach Area	6 × (27 × 39)	6 × (680 × 980)				
Die Thickness	3 78					
Top Metal	5 um AlSiCu + 1.15 um Ti/NiV/Ag (STM)					
Back Metal	0.65 um NiV/Ag					
Topside Passivation	Silicon Nitride plus Polyimide					
Wafer Diameter	200 mm					
Max Possible Die Per Wafer	136					

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#### **ABSOLUTE MAXIMUM RATINGS** ( $T_{VJ}$ = 25°C unless otherwise noted)

Parameter	Symbol	Ratings	Units
Collector-Emitter Voltage	V <sub>CES</sub>	650	V
Gate-Emitter Voltage	V <sub>GES</sub>	±20	V
DC Collector Current, limited by T <sub>VJ</sub> max	Ιc	(Note 1)	А
Pulsed Collector Current, $V_{GE}$ =15 V, tp limited by $T_{VJ}$ max (Note 2)	I <sub>CM</sub>	900	А
Short Circuit Withstand Time, V_{GE} = 15 V, V <sub>CE</sub> $\leq$ 400 V, T <sub>VJ</sub> $\leq$ 150 $^{\circ}$ C	t <sub>sc</sub>	5	μs
Operating Junction Temperature	T <sub>VJ</sub>	-40 to +175	°C
Storage Temperature Range	Tstg	+17 to +25	°C

1. Depends on the thermal properties of assembly

2. Not subject to production test - verified by design/characterization

## **ELECTRICAL CHARACTERISTICS OF THE IGBT** ( $T_{VJ}$ = 25°C unless otherwise noted)

Parameter	Symbol	Test Condition	Min.	Тур.	Max.	Units
Static Characteristics (Tested on wafers)						
Collector-Emitter Breakdown Voltage	BV <sub>CES</sub>	$V_{GE} = 0 V, I_C = 1 mA$	650	-	-	V
Collector-Emitter Saturation Voltage	V <sub>CE(SAT)</sub>	I <sub>C</sub> = 100 A, V <sub>GE</sub> = 15 V	-	1.25	1.55	V
Gate-Emitter Threshold Voltage	V <sub>GE(th)</sub>	$V_{GE}$ = $V_{CE}$ , $I_C$ = 300 mA	4.5	5.5	6.5	V
Collector Cut-Off Current	I <sub>CES</sub>	$V_{CE} = V_{CES}, V_{GE} = 0 V$	-	-	40	μA
Gate Leakage Current	I <sub>GES</sub>	$V_{GE} = V_{GES}, V_{CE} = 0 V$	-	-	±400	nA
On-chip temperature – sense diode voltage	V <sub>F</sub>	I <sub>F</sub> = 0.5 mA	2.0	2.4	2.8	V

#### Integrated Temp and Current Sensor Characteristics

(not subjected to production test - verified by design / characterization)

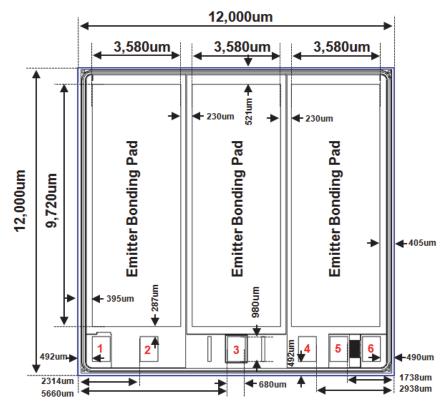
On-chip temperature-sense diode voltage	V <sub>F</sub>	$I_F$ = 0.5 mA, $T_{VJ}$ = 100 $^\circ\text{C}$	-	1.9	_	V
Emitter Sense Area Ratio	βarea	Sense Area/Total Area		1/10K		-
Emitter Current Sense Ratio	β10Ω	$I_{CE}$ = 300 A, $V_{GE}$ = 15 V $R_{SENSE}$ = 10 $\Omega$	-	18K	-	-

#### Electrical Characteristics (Not subjected to production test - verified by design/characterization)

Collector to Emitter Saturation Voltage	V <sub>GE</sub> = 15 V	$T_{VJ}$ = 25 °C	-	1.5	1.9	V	
		v <sub>GE</sub> = 15 v	$T_{VJ}$ = 175 °C	-	1.8	-	V
Input Capacitance	C <sub>IES</sub>			-	14.0	-	nF
Output Capacitance	C <sub>OES</sub>	V <sub>CE</sub> = 30 V, V <sub>C</sub> f = 1 MHz	<sub>AE</sub> = 0 V		690		pF
Reverse Transfer Capacitance	C <sub>RES</sub>				106	-	pF
Internal Gate Resistance	R <sub>G</sub>	f = 1 MHz		-	1.7	-	Ω
Total Gate Charge	Q <sub>G(Total)</sub>	V <sub>CE</sub> = 400 V, I <sub>C</sub> = 300 A V <sub>GE</sub> = 15 V			307	-	nC
Gate-to-Emitter Charge	Q <sub>GE</sub>			-	97	-	nC
Gate-to-Collector Charge	Q <sub>GC</sub>			-	64	-	nC
Turn-On Delay Time	t <sub>d(on)</sub>	V <sub>CE</sub> = 300 V, I	V <sub>CE</sub> = 300 V, I <sub>C</sub> = 300 A	-	167	-	ns
Rise Time	t <sub>r</sub>	$R_G = 15 \Omega$ $V_{GE} = 15 V$ Inductive Load	-	107	-	ns	
Turn-Off Delay Time	t <sub>d(off)</sub>		-	298	-	ns	
Fall Time	t <sub>f</sub>	T <sub>VJ</sub> = 25 °C		-	38	-	ns

Turn-On Delay Time	t <sub>d(on)</sub>	V <sub>CE</sub> = 300 V, I <sub>C</sub> = 300 A	-	130	-	ns
Rise Time	t <sub>r</sub>	$R_G = 15 \Omega$ V <sub>GE</sub> = 15 V	-	93	-	ns
Turn-Off Delay Time	t <sub>d(off)</sub>	Inductive Load	-	395	-	ns
Fall Time	t <sub>f</sub>	T <sub>VJ</sub> = 150 °C	-	78	-	ns

3. For ordering, technique and other information on Onsemi automotive bare die products, please contact automotivebaredie@onsemi.com



- 1. Current Sense Bonding Pad
- 2. Emitter Sense Bonding Pad
- 3. Gate Bonding Pad
- 4. Emitter Sense Bonding Pad
- 5. Temp Sense Anode Bonding Pad
- 6. Temp Sense Cathode Bonding Pad

Figure 1. Dimensional Outline and Pad Layout

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